Application/Control No. Applicant(s)/Patent Under Reexamination 09/493,601 DENNIS ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Tekchand Saidha 1652 **U.S. PATENT DOCUMENTS** Date **Document Number** Name Classification Country Code-Number-Kind Code MM-YYYY US-5,965,423 10-1999 Hillman et al. 435/198 Α US-В US-С US-D US-Ε US-F US-G USн US-US-USĸ US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY 0 Ρ Q R S **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) Sequence search alignment between Applicants' SEQ ID NO: 1 and Accession No. AF052112 Wang et al. [BBA 1437:157-169 (1999)]. A W

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.